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PATENT

#85-98 Response election
4-14-02
C. Wiles

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Jerry Schlagheck, et al.

For : DETECTION OF DEFECTS BY
THERMOGRAPHIC ANALYSIS

Serial No. : 09/648,140

Filed : August 25, 2000

Group Art Unit : 2859

Last Office Action : December 18, 2001

Attorney Docket No. : CLW 2 0132

Assistant Commissioner for Patents
Washington, D.C. 20231

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RESPONSE

Dear Sir:

Responsive to the Restriction Requirement mailed December 18, 2001, applicants elect Group II, drawn to a method for detecting a defect and obtaining a standard thermographic image as defined by claims 2-7. This election is made without traverse. Claim 1 may be withdrawn as being directed to a non-elected invention, although applicants

CERTIFICATE OF MAILING

I hereby certify that this Response and all other documents indicated therein as being enclosed are being deposited with the United States Postal Service in an envelope with sufficient postage for First Class Mail on the date indicated below and is addressed to the Assistant Commissioner for Patents, Washington, D. C. 20231.

Mary M. Schriner
Mary M. Schriner

March 18, 2002
Date

reserve the right to pursue the non-elected subject matter by way of a divisional application filed on or before issuance or abandonment of the present application, or any application claiming continuity therewith.

Applicants await substantive examination of the application.

Respectfully submitted,

FAY, SHARPE, FAGAN,
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